Searcl	ħΛ	lo	tes
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/627,402	VAEZ-IRAVANI ET AL.	
Examiner	Art Unit	
Han O Bhann	0077	

SEARCHED			
Class	Subclass	Date	Examiner
356	237.1- 237.5, 369, 239.1- 239.4	4/26/2005	НР
250	559.4	4/26/2005	HP
250	559.41	4/26/2005	HP
250	559.42	4/26/2005	HP
250	559.45	4/26/2005	HP
vpdate	Above	12/27/05	HP
,			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
356	AS ABD.	28/16/0	5 HP
18	ee a	Hache	d)
	Same	- as a	bore
		12/27/05	- HP

SEARCH NOTES (INCLUDING SÉARCH STRATEGY)			
	DATE	EXMR	
EAST update	4/26/2005	НР	
EART (Interference)	12/23/	H	
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